

Welcome **United States Patent and Trademark Office** 



FAQ Terms IEEE Peer Review

**Quick Links** 

 $\nabla$ 

<u>Help</u>

Welcome to IEEE Xplore

O- Home

What Can I Access?

O- Log-out

Tables of Contents

**Journals** & Magazines

 Conference **Proceedings** 

( )- Standards

Search

By Author

- Basic

Advanced

**Member Services** 

O Join IEEE C - Establish IEEE **Web Account** 

O- Access the **IEEE Member Digital Library** 

**IEEE Enterprise** 

( )- Access the **IEEE Enterprise File Cabinet** 

Try our New Full-text Search Prototype

1) Enter a single keyword, phrase, or Boolean expression. Example: acoustic imaging (means the phrase acoustic imaging plus any stem variations)

2) Limit your search by using search operators and field codes,

Example: optical <and> (fiber <or> fibre) <in> ti

3) Limit the results by selecting Search Options.

4) Click Search. See Search Examples

((call\* <near/1> admission\* <near/1> control\*) or cac\*) and (time\*stamp\* or (tim\* <near/2> stamp\*))

Start Search Clear

Note: This function returns plural and suffixed forms of the keyword(s).

Search operators: <and> <or> <not> <in> More

Field codes: au (author), ti (title), ab (abstract), jn (publication name), de (index term) More

Search Options: Select publication types: ✓ IEEE Journals ☑ IEE Journals ▼ IEEE Conference proceedings ✓ IEE Conference proceedings IEEE Standards Select years to search: From year: All Present 🗑 Organize search results by:

Results per page

Year In: Descending

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search | Join IEEE | Web Account | New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting | No Robots Please | Release Notes | IEEE Online Publications | Help | FAQ | Terms | Back to Top